

**Notice of References Cited**

Application/Control No.

10/730,014

Applicant(s)/Patent Under  
Reexamination  
SHIN ET AL.

Examiner

Christopher P. Schwartz

Art Unit

3683

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,612,823	09-1986	De Leeuw et al.	74/533
	B	US-4,841,798	06-1989	Porter et al.	74/501.5R
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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